PD - 9.1562A

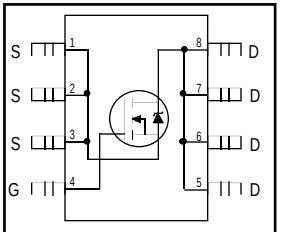
International
IOR Rectifier

PRELIMINARY

IRF9410

HEXFET® Power MOSFET

- Generation V Technology
- Ultra Low On-Resistance
- N-Channel MOSFET
- Surface Mount
- Very Low Gate Charge and Switching Losses
- Fully Avalanche Rated



Top View

V_{DSS} = 30V

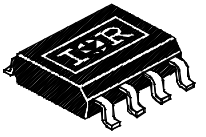
$R_{DS(on)}$ = 0.030Ω

Description

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The SO-8 has been modified through a customized leadframe for enhanced thermal characteristics and multiple-die capability making it ideal in a variety of power applications. With these improvements, multiple devices can be used in an application with dramatically reduced board space. The package is designed for vapor phase, infra red, or wave soldering techniques.

Recommended upgrade: IRF7403 or IRF7413
Lower profile/smaller equivalent: IRF7603


SO-8

Absolute Maximum Ratings (T_A = 25°C Unless Otherwise Noted)

		Symbol	Maximum	Units
Drain-Source Voltage		V_{DS}	30	V
Gate-Source Voltage		V_{GS}	± 20	
Continuous Drain Current⑤	T_A = 25°C	I_D	7.0	A
	T_A = 70°C		5.8	
Pulsed Drain Current		I_{DM}	37	
Continuous Source Current (Diode Conduction)		I_S	2.8	
Maximum Power Dissipation ⑤	T_A = 25°C	P_D	2.5	W
	T_A = 70°C		1.6	
Single Pulse Avalanche Energy ②		E_{AS}	70	mJ
Avalanche Current		I_{AR}	4.2	A
Repetitive Avalanche Energy		E_{AR}	0.25	mJ
Peak Diode Recovery dv/dt ③		dv/dt	5.0	V/ ns
Junction and Storage Temperature Range		T_J, T_{STG}	-55 to + 150	°C

Thermal Resistance Ratings

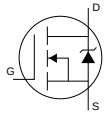
Parameter	Symbol	Limit	Units
Maximum Junction-to-Ambient ⑤	$R_{\theta JA}$	50	°C/W

Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	30	——	——	V	V_{GS} = 0V, I_D = 250µA
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	——	0.024	——	V/°C	Reference to 25°C, I_D = 1mA
$R_{DS(on)}$	Static Drain-to-Source On-Resistance	——	0.024	0.030	Ω	V_{GS} = 10V, I_D = 7.0A ④
		——	0.032	0.040		V_{GS} = 5.0V, I_D = 4.0A ④
		——	0.037	0.050		V_{GS} = 4.5V, I_D = 3.5A ④
$V_{GS(th)}$	Gate Threshold Voltage	1.0	——	——	V	V_{DS} = V_{GS}, I_D = 250µA
g_{fs}	Forward Transconductance	——	14	——	S	V_{DS} = 15V, I_D = 7.0A
I_{DSS}	Drain-to-Source Leakage Current	——	——	2.0	µA	V_{DS} = 24V, V_{GS} = 0V
		——	——	25		V_{DS} = 24V, V_{GS} = 0V, T_J = 55°C
I_{GSS}	Gate-to-Source Forward Leakage	——	——	100	nA	V_{GS} = 20V
	Gate-to-Source Reverse Leakage	——	——	-100		V_{GS} = -20V
Q_g	Total Gate Charge	——	18	27	nC	I_D = 2.0A
Q_{gs}	Gate-to-Source Charge	——	2.4	3.6		V_{DS} = 15V
Q_{gd}	Gate-to-Drain ("Miller") Charge	——	4.9	7.4		V_{GS} = 10V, See Fig. 10 ④
$t_{d(on)}$	Turn-On Delay Time	——	7.3	15	ns	V_{DD} = 25V
t_r	Rise Time	——	8.3	17		I_D = 1.0A
$t_{d(off)}$	Turn-Off Delay Time	——	23	46		R_G = 6.0Ω, V_{GS} = 10V
t_f	Fall Time		17	34		R_D = 25Ω ④
C_{iss}	Input Capacitance	——	550	——	pF	V_{GS} = 0V
C_{oss}	Output Capacitance		260			V_{DS} = 25V
C_{rss}	Reverse Transfer Capacitance	——	100	——		f = 1.0MHz, See Fig. 9

Source-Drain Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	——	——	2.8	A	MOSFET symbol showing the integral reverse p-n junction diode.
I_{SM}	Pulsed Source Current (Body Diode) ①	——	——	37		
V_{SD}	Diode Forward Voltage	——	0.78	1.0	V	T_J = 25°C, I_S = 2.0A, V_{GS} = 0V ③
t_{rr}	Reverse Recovery Time	——	40	80	ns	T_J = 25°C, I_F = 2.0A
Q_{rr}	Reverse RecoveryCharge	——	63	130	nC	di/dt = 100A/µs ③



Notes:

① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)

② Starting T_J = 25°C, L = 6.6mH R_G = 25Ω, I_{AS} = 4.6A.

③ I_{SD} ≤ 4.6A, di/dt ≤ 120A/µs, V_{DD} ≤ $V_{(BR)DSS}$, T_J ≤ 150°C

④ Pulse width ≤ 300µs; duty cycle ≤ 2%.

⑤ Surface mounted on FR-4 board, t ≤ 10sec.

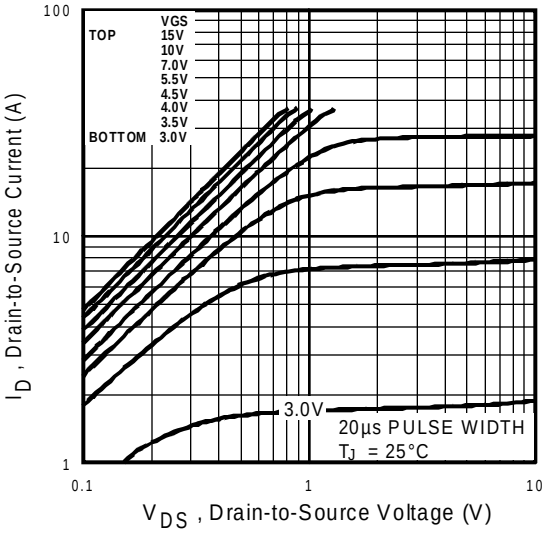


Fig 1. Typical Output Characteristics

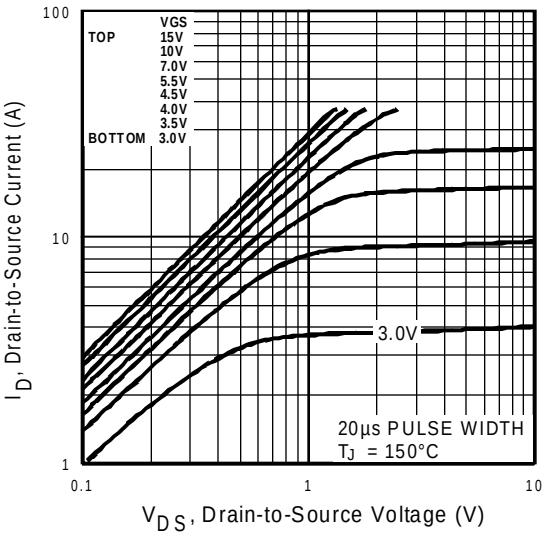


Fig 2. Typical Output Characteristics

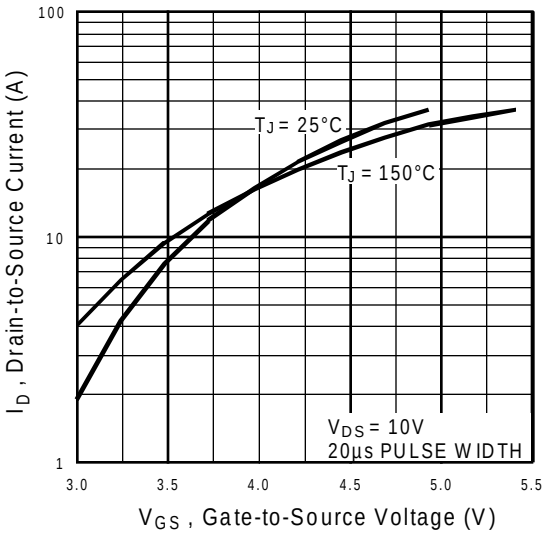


Fig 3. Typical Transfer Characteristics

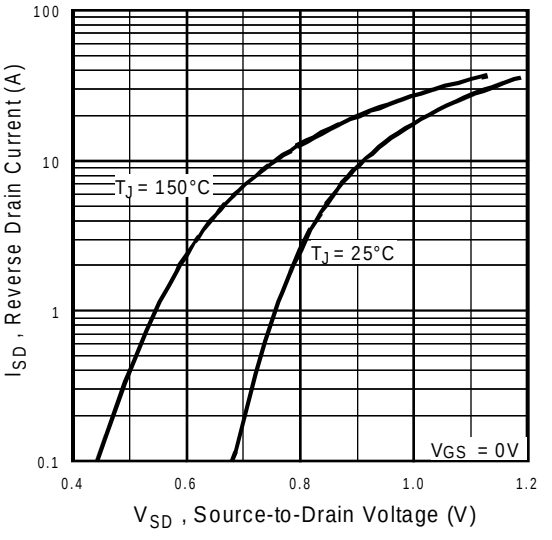


Fig 4. Typical Source-Drain Diode Forward Voltage

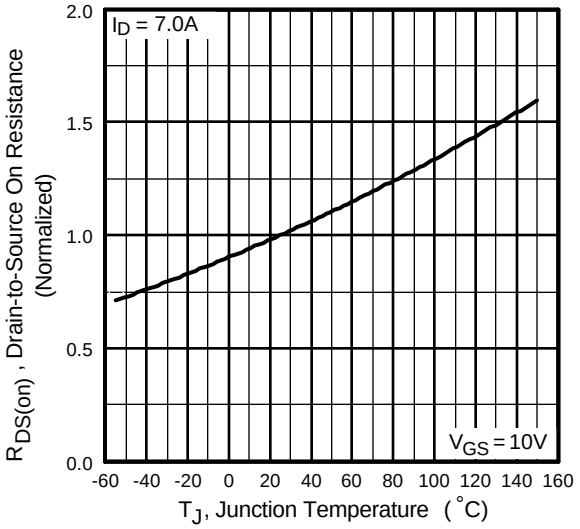


Fig 5. Normalized On-Resistance Vs. Temperature

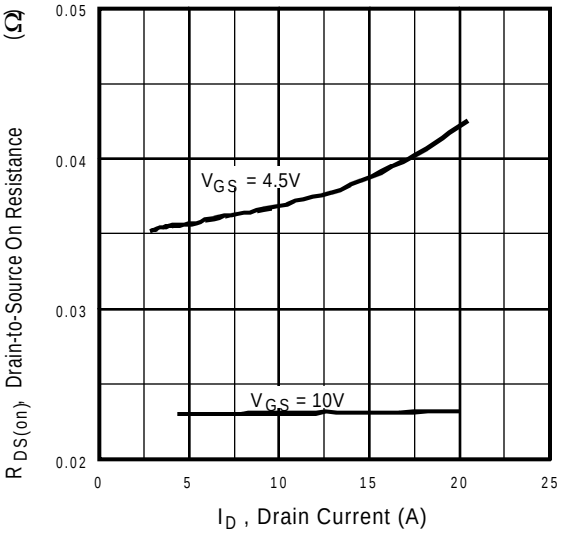


Fig 6. Typical On-Resistance Vs. Drain Current

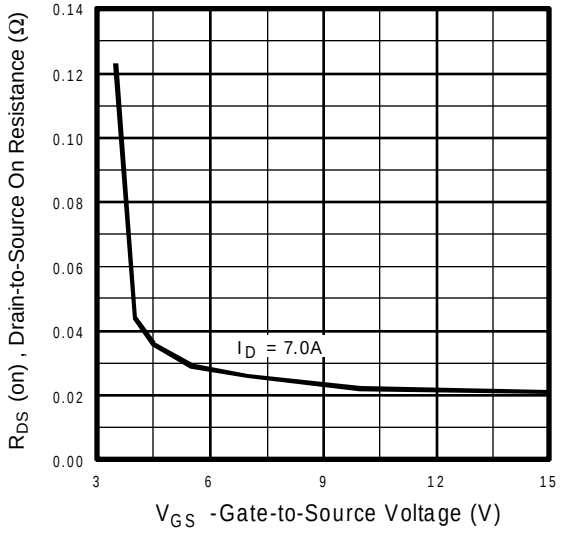


Fig 7. Typical On-Resistance Vs. Gate Voltage

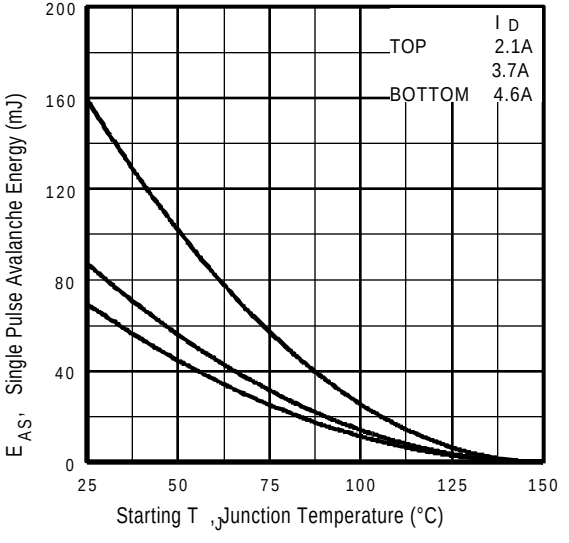


Fig 8. Maximum Avalanche Energy Vs. Drain Current

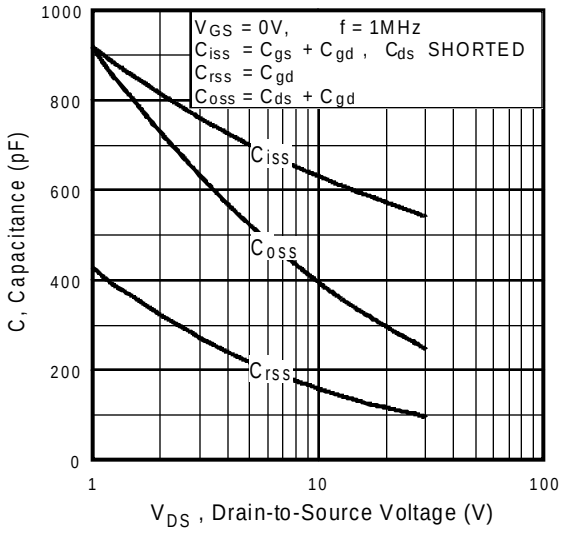


Fig 9. Typical Capacitance Vs. Drain-to-Source Voltage

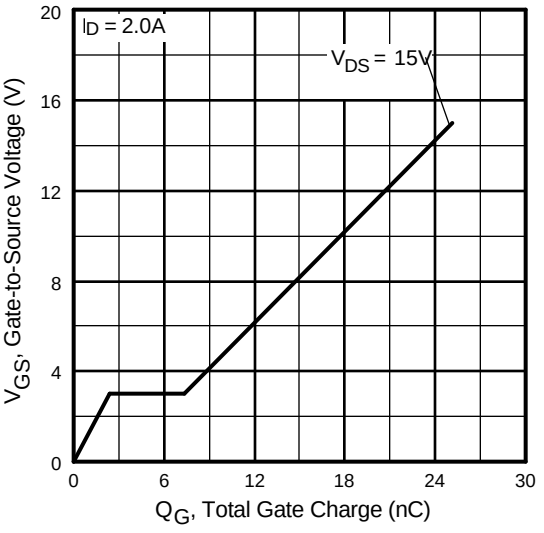


Fig 10. Typical Gate Charge Vs. Gate-to-Source Voltage

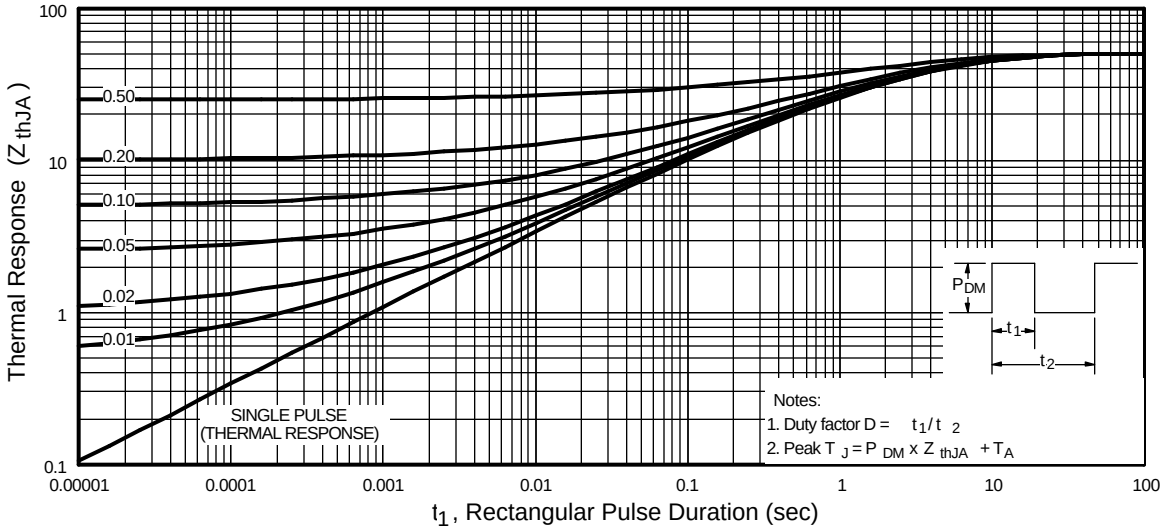
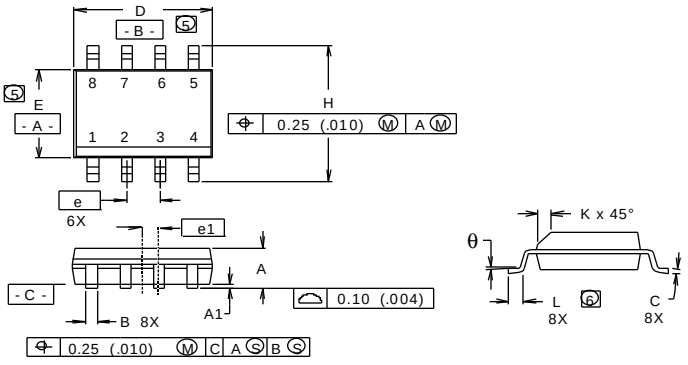


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

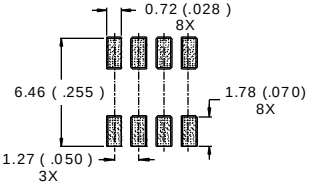
Package Outline

SO8 Outline



DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.0532	.0688	1.35	1.75
A1	.0040	.0098	0.10	0.25
B	.014	.018	0.36	0.46
C	.0075	.0098	0.19	0.25
D	.189	.196	4.80	4.98
E	.150	.157	3.81	3.99
e	.050 BASIC		1.27 BASIC	
e1	.025 BASIC		0.635 BASIC	
H	.2284	.2440	5.80	6.20
K	.011	.019	0.28	0.48
L	0.16	.050	0.41	1.27
θ	0°	8°	0°	8°

RECOMMENDED FOOTPRINT



NOTES:

1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M-1982.
2. CONTROLLING DIMENSION : INCH.
3. DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
4. OUTLINE CONFORMS TO JEDEC OUTLINE MS-012AA.

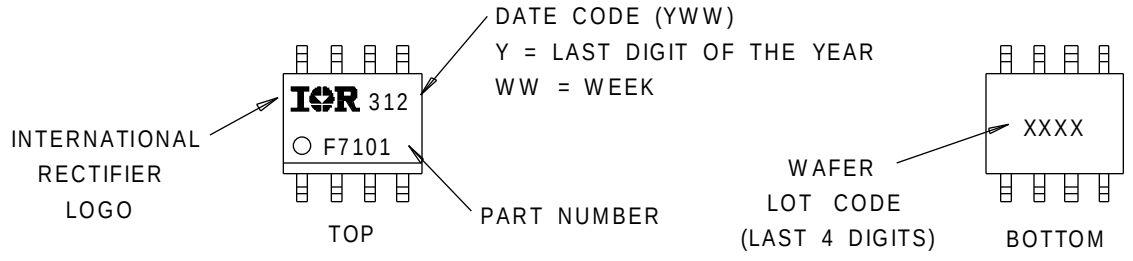
5 DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS
MOLD PROTRUSIONS NOT TO EXCEED 0.25 (.006).

6 DIMENSIONS IS THE LENGTH OF LEAD FOR SOLDERING TO A SUBSTRATE..

Part Marking Information

SO8

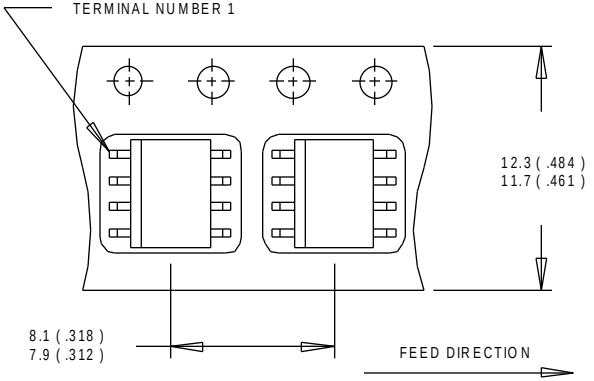
EXAMPLE : THIS IS AN IRF7101



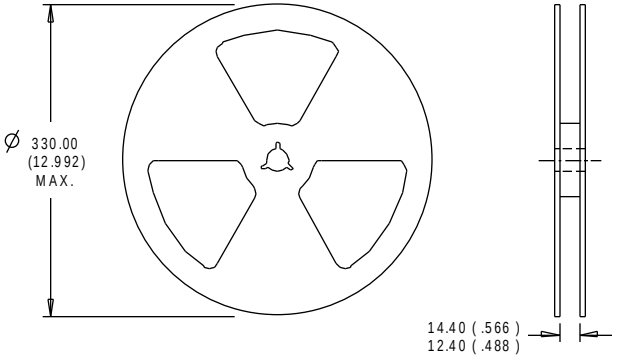
Tape & Reel Information

SO8

Dimensions are shown in millimeters (inches)



NOTES:
1. CONTROLLING DIMENSION : MILLIMETER.
2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS(INCHES).
3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES :
1. CONTROLLING DIMENSION : MILLIMETER.
2. OUTLINE CONFORMS TO EIA-481 & EIA-541.

International
IOR Rectifier

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